

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of Applicants:	Date: February 9, 2010
Beaman et al.	Group Art Unit: 2829
Serial No.: 09/251,988	Examiner: J. M. Hollington
Filed: February 17, 1999	Docket No.: YO999-088
For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY	

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT SUBMITTED WITH RCE**

Sir:

This is an amendment submitted with an RCE.

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 5 of this paper.